TESLA Collaboration Meeting

Thursday, 31 March 2005

Parallel Session WG-1 + WG-2 - 1b--4a (09:00 - 10:30)

time	[id] title	presenter
09:00	[28] DC Field Emission Scanning	DANGWAL, ARTI
09:15	[29] New Instrumentation for Surface Roughness and Contamination Control of Nb samples	MUELLER, GUENTHER
09:30	[30] R&D towards Understanding the “Q-drop”	KNEISEL, PETER
09:45	[31] Preliminary Results from Large Grain and Single Crystal Niobium cavities	KNEISEL, PETER